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<u>L4</u>	11 and 13	1	<u>L4</u>
<u>L3</u>	(window\$ near5 (mov\$ or slid\$)) and (data near5 chunk\$)	24	<u>L3</u>
<u>L2</u>	L1 and (window\$ near5 (mov\$ or slid\$))	6	<u>L2</u>
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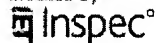
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